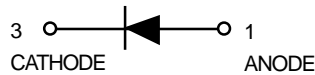


Silicon Hot –Carrier Diodes

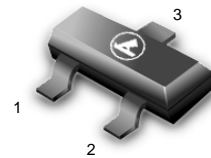
These devices are designed primarily for high–efficiency UHF and VHF detector applications. They are readily adaptable to many other fast switching RF and digital applications. They are supplied in an inexpensive plastic package for low–cost,high–volume consumer and industrial/commercial requirements. They are also available in a Surface Mount package.

- Extremely Low Minority Carrier Lifetime – 15 ps (Typ)
- Very Low Capacitance – 1.0 pF @ $V_R = 20$ V
- High Reverse Voltage – to 70 Volts
- Low Reverse Leakage – 200 nA (Max)



**MBD701
MMBD701LT1**

**70 VOLTS
HIGH-VOLTAGE
SILICON HOT-CARRIER
DETECTOR AND SWITCHING
DIODES**



**CASE 318-08, STYLE8
SOT- 23 (TO-236AB)**

MAXIMUM RATINGS ($T_J = 125^\circ\text{C}$ unless otherwise noted)

Rating	Symbol	MBD701		MMBD701LT1		Unit
		Value	Value	Value	Value	
Reverse Voltage	V_R	70				Volts
Forward Power Dissipation @ $T_A = 25^\circ\text{C}$	P_F	280	200			mW
Derate above 25°C		2.8	2.0			mW/ $^\circ\text{C}$
Operating Junction Temperature Range	T_J	–55 to +125				$^\circ\text{C}$
Storage Temperature Range	T_{stg}	–55 to +150				$^\circ\text{C}$

DEVICE MARKING

MMBD701LT1 = 5H

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	typ	Max	Unit
Reverse Breakdown Voltage ($I_R = 10\mu\text{A}$)	$V_{(BR)R}$	70	—	—	Volts
Total Capacitance ($V_R = 20$ V, $f = 1.0$ MHz) Figure 1	C_T	—	0.5	1.0	pF
Reverse Leakage ($V_R = 35$ V) Figure 3	I_R	—	9.0	200	nA _{dc}
Forward Voltage ($I_F = 1.0$ mA _{dc}) Figure 4	V_F	—	0.42	0.5	V _{dc}
Forward Voltage ($I_F = 10$ mA _{dc}) Figure 4	V_F	—	0.7	1.0	V _{dc}

NOTE: MMBD701LT1 is also available in bulk packaging. Use MMBD701L as the device title to order this device in bulk.

MBD701 MMBD701LT1

TYPICAL ELECTRICAL CHARACTERISTICS

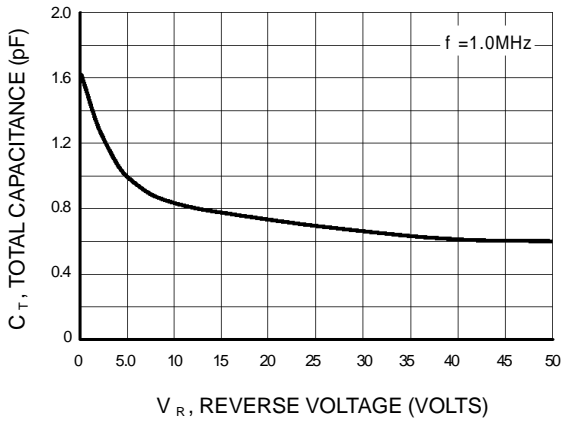


Figure 1. Total Capacitance

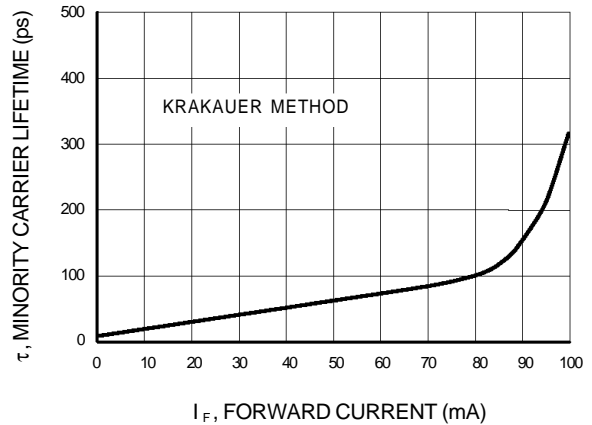


Figure 2. Minority Carrier Lifetime

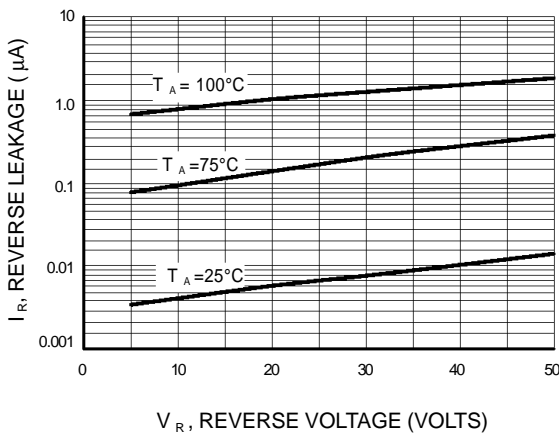


Figure 3. Reverse Leakage

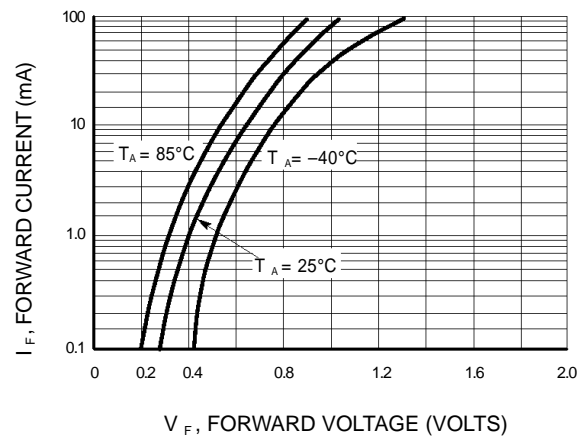


Figure 4. Forward Voltage

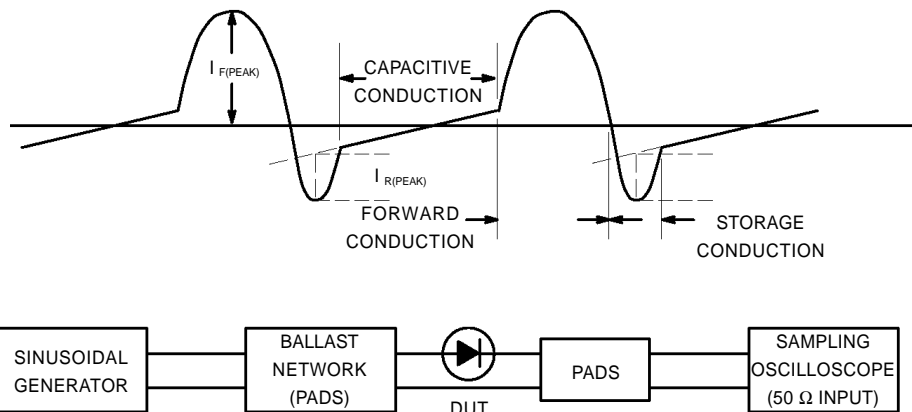


Figure 5. Krakauer Method of Measuring Lifetime